

Supplementary Information

Indium-Tin-Oxide free transparent electrode using plasmon frequency conversion layer**

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AFM measurement

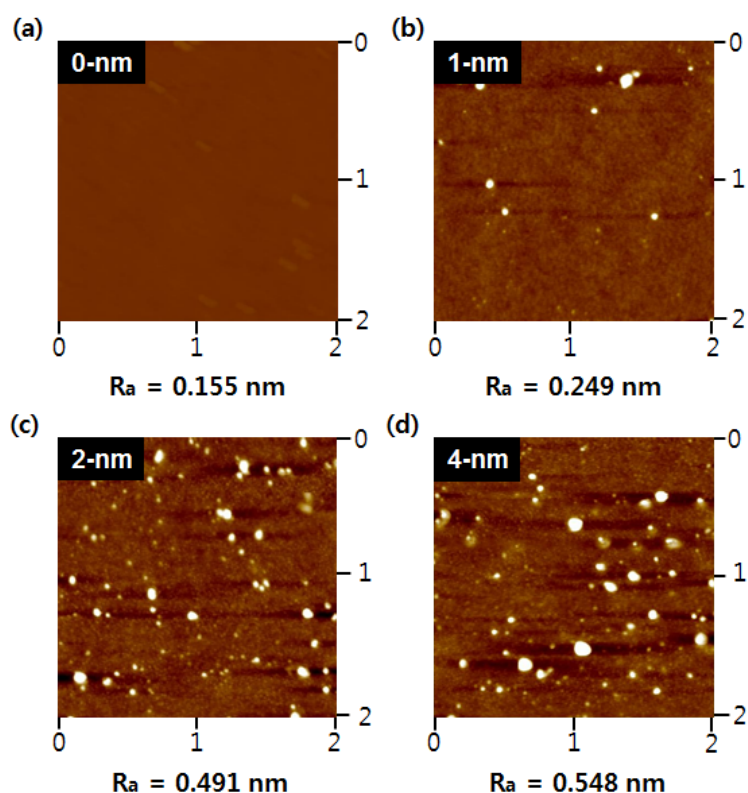


Fig. 1S AFM (Tapping-mode) height images of a) 0 nm, b) 1 nm, c) 2 nm, and d) 4 nm-thick Al on 1 nm-thick LiF deposited glass substrates.